Abstracts

A New Automated Noise and Gain Parameter Measurement System

V.A. Hirsch and T.H. Miers. "A New Automated Noise and Gain Parameter Measurement System." 1987 MTT-S International Microwave Symposium Digest 87.1 (1987 Vol. I [MWSYM]): 517-520.

This paper describes an automated noise and gain parameter measurement system which operates to 26.5 GHz. A new test set configuration and thorough measurement techniques are employed to minimize errors. The noise and gain parameters for an 0.3 µm gate GaAs FET at 10 and 22 GHz are presented.

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